

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
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*	B	US-5,655,961	08-1997	Acres et al.	463/27
*	C	US-2001/0048507 a1	12-2001	Thomas et al.	353/10
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**NON-PATENT DOCUMENTS**

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	U	Cees van Berkel and John A. Clarke, "Characterisation and Optimisation of 3D-LCD Module Design", Feb 11-14 1997, SPIE International Conference on Electronic Imaging
	V	Cees van Berkel, A R Franklin and J R Mansell, "Design and Applications of Multiview 3D-LCD", Oct 1996, 1996 EuroDisplay Conference, pp. 109-112
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.